

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): UENOYAMA  
Serial No.: Unknown  
Filed: Concurrently herewith  
Title: MAGNETIC SENSOR ADJUSTING  
METHOD, MAGNETIC SENSOR  
ADJUSTING DEVICE AND  
MAGNETIC SENSOR

Atty. Dkt.: 12-044  
Group Art Unit:  
Examiner:

Commissioner for Patents  
Arlington, VA 22202

Date: March 30, 2004

**INFORMATION DISCLOSURE STATEMENT**

Sir:

Pursuant to 37 C.F.R. §1.56, the reference(s) listed on the attached Form PTO-1449 is/are submitted for consideration by the Examiner without any admission that it/they constitute(s) statutory prior art, or without any admission that it/they contain(s) subject matter that anticipates the invention or renders the invention obvious to a person of ordinary skill in the art.

The Examiner is requested to initial the attached PTO Form-1449 and to return a copy of same to the undersigned attorney as proof that the listed reference(s) has/have been considered and made of record.

Respectfully submitted,



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FORM PTO-1449	ATTY. DKT NO.	12-044	SER. NO.
	APPLICANT	UENOYAMA	
	FILING DATE	March 30, 2004	GROUP

**REFERENCE DESIGNATION**

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
		6,046,584 (English counterpart of JP-A-H10-103145 which is discussed in pages 1-4 of the spec.)	Apr. 4, 2000	Nakane et al.		
		6,194,893 (English counterpart of JP-A-H11-304414 which is discussed in pages 1-2 of the spec.)	Feb. 27, 2001	Yokotani et al.		
		6,452,381 (English counterpart of JP-A-H11-237256 which is discussed in pages 1-2 of the spec.)	Sep. 17, 2002	Nakatani et al.		

**FOREIGN PATENT DOCUMENTS**

**TRANSLATION**

		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO (Abstract)
		JP-A-H10-103145 (Discussed in pages 1-4 of the spec.)	4/21/98	JAPAN					X
		JP-A-H11-237256 (Discussed in pages 1-2 of the spec.)	8/31/99	JAPAN					X
		JP-A-H11-304414 (Discussed in pages 1-2 of the spec.)	11/5/99	JAPAN					X

\* Full English text is available in machine-translated form in JPO (Japanese Patent Office) English language web site at <http://www1.ipdl.jpo.go.jp/PA1/cgi-bin/PA1INDEX>.

**OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)**

EXAMINER		DATE CONSIDERED